



US006894523B2

(12) **United States Patent**
Neeb

(10) Patent No.: **US 6,894,523 B2**
(45) Date of Patent: **May 17, 2005**

(54) **SYSTEM AND METHOD FOR TESTING SEMICONDUCTOR DEVICES**

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(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 0 days.

(21) Appl. No.: **10/612,553**

(22) Filed: **Jul. 1, 2003**

(65) **Prior Publication Data**

US 2005/0001647 A1 Jan. 6, 2005

(51) Int. Cl.⁷ **G01R 31/26**

(52) U.S. Cl. **324/765; 324/158.1**

(58) Field of Search **324/754-758, 324/761-762, 765, 158.1**

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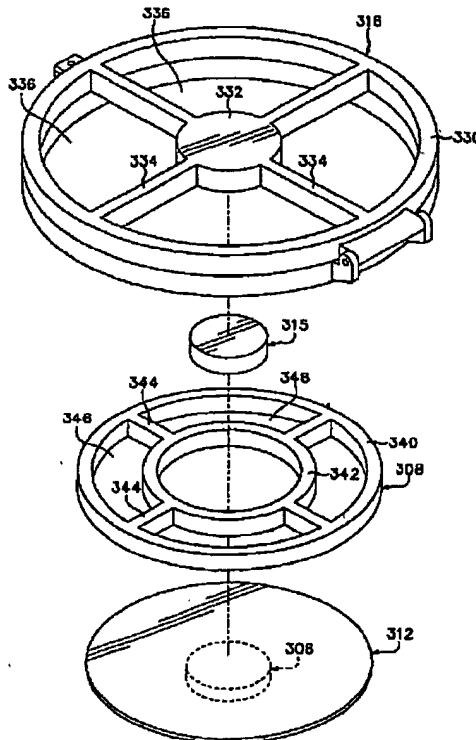
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(57) **ABSTRACT**

The invention(s) relates to semiconductor test system and method that isolates and counteracts forces that bend test equipment resulting in improved manufacturing yield and throughput. The system includes a force retainer fixedly mounted on a material handler and a force locator positioned between the force retainer and a circuit board. Together, the force retainer and locator prevent the circuit board from bending. Other embodiments are illustrated and described.

18 Claims, 4 Drawing Sheets



EXH A
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